

R3115Z Series Reliability Test Report

303115Z0-Ver.A

FUNCTION : Voltage Detector ICs

PACKAGE : WL-CSP-4

Lead free

No.	TEST ITEM	TEST CONDITION	(*)PRE-CONDITION	TIME	r/n
1	High Temp. Operating Life	Ta=125°C VDD=Vopt max. Static	Non	1000h	0/32
2	Temp. Humidity Bias	Ta=85°C RH=85% VDD=Vopt max. Static	(1)+(2)	1000h	0/22
3	High Temp. Storage	Ta=150°C	Non	1000h	0/22
4	Low Temp. Storage	Ta=-65°C	Non	1000h	0/22
5	Temp. Humidity	Ta=85°C RH=85%	(1)+(2)	1000h	0/22
6	Temp. Cycle	Ta=-65 to 150°C(30-5-30min)	(1)+(2)	100cycles	0/11
7	Thermal Shock	Ta=-65 to 150°C(5min-10s-5min)	(1)+(2)	100cycles	0/11
8	USPCBT	Ta=125°C RH=85% 2X10 ⁵ Pa VDD=Vopt max. Static	(1)+(2)	100h	0/11
9	USPCT	Ta=125°C RH=85% 2X10 ⁵ Pa	(1)+(2)	100h	0/11
10	Resistance To Soldering Heat	IR Reflow (See Fig.1)	(1)	3times	0/88
11	ESD(1)	C=200pF R=0 ohm ±150V	Non	5times	0/11
12	ESD(2)	C=100pF R=1.5k ohm ±2.0kV	Non	3times	0/11
13	Latch-up	Pulse Current Injecting Method ±100mA	Non	Once	0/11

Criteria : The electrical characteristics prescribed in the individual specifications shall be satisfied.

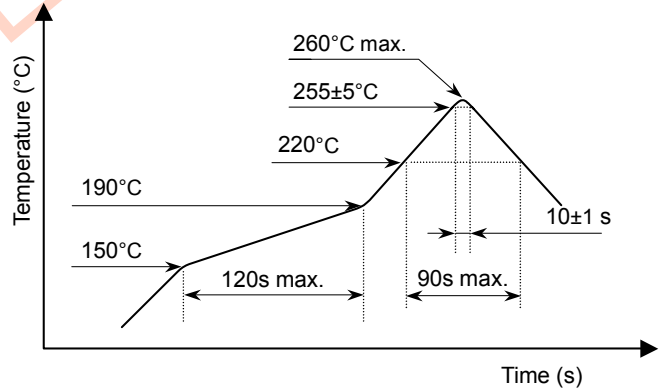
***)Pre-Condition**

The test shall be performed this pre-condition before testing.

- (1)Ta=85°C, RH=85%, storage 168h
- (2)IR Reflow soldering heat stress (3times)
- (3)In steam, storage=4h

[Moisture Sensitivity Level]
MSL Level = 1 (J-STD-020)

**HEATING TREATMENT CONDITION
OF INFRARED-RAY REFLOW**



Conclusion : We have good results of reliability test.